

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NIIMI ET AL.	
		Examiner Janis L. Dote	Art Unit 1756	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0033428 A1	02-2004	Niimi, Tatsuya	430/59.5
*	B	US-2003/0104295 A1	06-2003	Niimi, Tatsuya	430/59.4
*	C	US-2002/0076633 A1	06-2002	Niimi, Tatsuya	430/59.6
*	D	US-2002/0051654 A1	05-2002	Niimi et al.	399/159
*	E	US-2001/0022343 A1	09-2001	Sakai et al.	250/234
*	F	US-6,853,823 B2	02-2005	Sugino et al.	399/159
*	G	US-6,120,955	09-2000	Tokutake et al.	430/65
*	H	US-5,430,526	07-1995	Ohkubo et al.	399/159
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11-140337	05-1999	Japan	--	--
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	USPTO English-language translation of JP 11-140337 (pub. 05-1999).
	V	Ladd, M.F.C., et al., Structure Determination by X-ray Crystallography, Plenum Press (NY), 1985, pp. 424-426.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.